



U.S. Department of Commerce Patent and Trademark Office				ATTY DOCKET NO. BMID 9958 CIP US		SERIAL NO. 10/601,144	
INFORMATION DISCLOSURE STATEMENT				APPLICANT BHULLAR et al.		GROUP <del>124</del> 3700	
				FILING DATE 06/20/2003			

  

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
ga	1	4,081,653	3-28-1978	Koo et al.	219	121
	2	4,131,484	12-26-78	Caruso, et al.	134	1
	3	4,414,059	11-8-83	Blum et al.	156	659.1
	4	4,684,437	8-4-1987	Donelon et al.	156	643
	5	4,865,873	9-12-1989	Cole et al.	427	53.1
	6	4,874,500	10-17-89	Madou et al.	204	412
	7	4,897,173	1-30-90	Nankai et al.	204	403
	8	5,018,164	5/21/91	Brewer et al.	372	109
	9	5,089,103	2-18-92	Swedberg	204	182.8
	10	5,104,480	4-14-92	Wojnarowski et al.	156	643
	11	5,120,420	6-9-92	Nankai et al.	204	403
	12	5,264,103	11/93	Yoshioka et al.	204	403
	13	5,266,179	11-30-93	Nankai et al.	204	401
	14	5,288,636	2-22-94	Pollmann et al.	435	288
	15	5,334,279	8-2-94	Gregoire	156	630
	16	5,336,388	8-9-94	Leader et al.	204	406
	17	5,382,346	1-17-95	Uenoyama et al.	204	403
	18	5,390,412	2-21-95	Gregoire	29	848
	19	5,391,250	2-21-95	Cheney II et al.	156	268
	20	5,395,504	3-7-95	Saurer et al.	204	403
	21	5,413,690	5-9-95	Kost et al.	204	403
	22	5,414,224	5-9-95	Adasko et al.	174	262
	23	5,426,850	6-27-95	Fukutomi et al.	29	848
	24	5,437,999	5-13-97	Diebold et al.	435	288
	25	5,451,722	9-19-95	Gregoire	174	261
	26	5,465,480	11-14-95	Karl et al.	29	825
	27	5,496,453	3-5-96	Uenoyama et al.	205	777.5
	28	5,508,171	4-16-96	Walling et al.	205	777.5
	29	5,509,410	4-23-96	Hill et al.	128	637
	30	5,512,489	04-1996	Girault et al.	205	777.5
	31	5,575,930	11-19-96	Tietje-Girault et al.	216	65
	32	5,576,073	11-19-96	Kickelhain	427	555
	33	5,589,326	12-31-96	Deng et al.	435	4
	34	5,593,739	1-14-97	Kickelhain	427	555
	35	5,628,890	5-13-97	Carter et al.	204	403
	36	5,635,054	06-1997	Girault et al.	205	775
	37	5,682,884	11-4-97	Hill et al.	128	637
	38	5,708,247	1-13-98	McAleer et al.	204	403
	39	5,755,953	5-26-98	Henning et al.	205	778
	40	5,773,319	6-30-98	Chu et al.	438	39
	41	5,739,039	04-1998	Girault et al.	436	149
	42	5,758,398	6-2-98	Rijnbeek et al	29	25.42
	43	5,759,364	6-2-98	Charlton et al.	204	403
	44	5,762,770	6-9-98	Pritchard et al.	204	403
	45	5,798,031	8-25-98	Charlton et al.	204	403
	46	5,948,289	09-07-99	Noda et al.	219	121.69
	47	5,955,179	9/99	Kickelhain et al.	428	210
ga	48	5,956,572	9-21-99	Kidoguchi et al.	438	96

  

Examiner <i>gaules</i>	Date Considered 11/7/05
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\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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INFORMATION DISCLOSURE STATEMENT				APPLICANT BHULLAR et al.		FILING DATE 06/20/2003	
				GROUP 17433200			
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
QA	49	5,965,001	10-12-99	Chow et al.	204	600	
QA	50	6,004,441	12-21-99	Fujiwara et al.	204	412	
QA	51	6,103,033	8-15-00	Say et al.	156	73.1	
QA	52	6,134,461	10-17-00	Say et al.	600	345	
QA	53	6,165,594	12-26-00	Moh et al.	428	207	
QA	54	6,175,752 B1	1-16-01	Say et al.	600	345	
QA	55	6,203,952 B1	3-20-01	O'Brien et al.	430	17	
QA	56	6,258,229 B1	7-01	Winarta et al.	205	403	
QA	57	6,287,451 B1	9-11-01	Winarta et al.	205	777.5	
QA	58	6,299,757 B1	10-9-01	Feldman et al.	205	775	
QA	59	6,309,526 B1	10-30-01	Fujiwara et al.	204	403	
QA	60	6,338,790 B1	1-15-02	Feldman et al.	205	777.5	
QA	61	6,399,258 B2	6-4-02	O'Brien et al.	430	17	
QA	61b	6,662,439	12-16-03	Bhullar	29	825	
QA	62	6,696,008 B2	2-24-04	Bradinger	264	400	5-25-01
QA	63	US 2001/0006766 A1	7-5-01	O'Brien et al.			1-12-01
QA	64	US 2003/0088166 A1	5-8-2003	Say et al.			11-11-2002
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
QA	65	0 480 703 A2	4/92	EP			--
QA	66	0 480 703 B1	3/97	EP			--
QA	67	0 875 754	11-4-98	EP			--
QA	68	1 152 239 A1	11-14-00	EP			--
QA	69	1 195 441 A1	4-10-02	EP			--
QA	70	1 202 060 A1	5-2-2002	EP			--
QA	71	1 203 956 A2/A3	5-8-2002	EP			--
QA	72	1 288 654 A1	03-05-03	EP			--
QA	74	2000-121594 abstract	April 00	JP			--
QA	75	56100451	Aug 81	JP			yes (abstract)
QA	76	11297890	Oct. 99	JP			yes (abstract)
QA	77	7-66499	3-10-95	JP			yes (abstract)
QA	78	7-290751	11-7-95	JP			yes (abstract)
QA	79	9-260697	10-3-97	JP			yes (abstract)
QA	80	10-241992 abstract	9-1-98	JP			--
QA	81	10-303444 abstract	11-1-98	JP			--
QA	83	10-275959	10-1-98	JP			--
QA	84	5-31 5703	11-26-93	JP			yes (abstract)
QA	85	10-52780 abstract	2-24-98	JP			yes (abstract)
Examiner c.g. Arbes				Date Considered 1/17/05			

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		APPLICANT BHULLAR et al.	
		FILING DATE 06/20/2003	GROUP <del>1743</del> 3700
INFORMATION DISCLOSURE STATEMENT			
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)			
<i>Cy</i>	116	LPKF MicrolineLaser II, LPKF Laser & Electronics AG; LPKF; Art.-Nr. 107645-2 (01/00) (2pp.)	
<i>Cfa</i>	117	Microline Solutions, LPKF Laser & Electronics AG; LPKF; Art.-Nr. 107658-1 (01/00) (3pp.)	
Examiner <i>Agarbes</i>		Date Considered <i>11/7/05</i>	

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		FILING DATE 06/20/2003		GROUP 1743 3700	
INFORMATION DISCLOSURE STATEMENT					
FOREIGN PATENT DOCUMENTS					
Cl. A	86	WO 91/02391	2-21-91	PCT	--
Cl. A	87	WO 91/08474	6-13-91	PCT	--
Cl. A	88	WO 95/22881	8-24-95	PCT	--
Cl. A	89	WO 98/35225	8-13-98	PCT	--
Cl. A	90	WO 98/49773	Dec 98	PCT	--
Cl. A	91	WO 99/13101	3-18-99	PCT	--
Cl. A	92	WO 99/30152	6-17-99	PCT	--
Cl. A	93	WO 99/45387	9-10-99	PCT	--
Cl. A	94	WO 98/55856	12-10-98	PCT	--
Cl. A	95	WO 00/42472 A1	7-20-00	PCT	--
Cl. A	96	WO 00/73778	12/2000	PCT	--
Cl. A	97	WO 00/73785	12/2000	PCT	--
Cl. A	98	WO 01/36953	5-25-01	PCT	yes abstract
Cl. A	99	WO 01/75438	10-11-01	PCT	--
Cl. A	100	WO 01/25775	4-12-01	PCT	--
Cl. A	101	WO 01/92884	12-6-01	PCT	yes abstract
Cl. A	102	WO 02/086483	10-31-02	PCT	yes abstract
Cl. A	103	WO 02/27074	4-4-02	PCT	yes abstract
Cl. A	104	WO 02/086483	10/2002	PCT	yes abstract
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)					
*Examiner Initial	105	Tender, L. et al., "Electrochemical Patterning of Self-Assembled Monolayers onto Microscopic Arrays of Gold Electrodes Fabricated by Laser Ablation, <i>Langmuir</i> , 1996, 12, 5515-5518.			
Cl. A	106	Tahhan, Isam, "Biocompatible Microstructuring of Polymers and Electrodes with an Excimer Laser", MEDICS Workshop 2000 Speakers Abstracts, 2 pp.			
Cl. A	107	Sheppard, Jr. et al. "Electrical Conductivity Measurements Using Microfabricated Interdigitated Electrodes", <i>Anal. Chem.</i> , 1993, 65, 1199-1202.			
Cl. A	108	Srinivasan R., et al. "Ultraviolet Laser Ablation of Organic Polymers", <i>Chem. Rev.</i> , 1989, 89, 1303-1316.			
Cl. A	109	Zongyi, Q., et al. "Excimer Laser Patterning on Thin Polymer Surfaces for Electrochemical Gas Sensors", Polymer Physics Laboratory, Changchun Institute of Applied Chemistry, Chinese Academy of Sciences, Changchun, Peop. Rep. China., Proceedings of the International Conference on Lasers (1999) 21 <sup>st</sup> (Abstract) 1pp.			
Cl. A	111	Vaucher et al. "Laser Direct Imaging and Structuring: An Update", <a href="http://www.circuitres.com/CDA/ArticleInformation/features/BNP_Features_Item/0.2.1.33.81173.00.html">http://www.circuitres.com/CDA/ArticleInformation/features/BNP_Features_Item/0.2.1.33.81173.00.html</a> ; posted on: 08/01/2002.			
Cl. A	112	Wu, J. et al. "Single-shot Excimer Laser Ablation of Thick Polymer Resists on Metallic Substrates", <i>AMP Journal of Technology</i> VOL 1 November, 1991, 69-79.			
Cl. A	113	Srinivasan, R., "Ablation of Polymers and Biological Tissue by Ultraviolet Lasers", <i>Science</i> , Vol. 234, October 21, 1986, 559-564.			
Cl. A	114	Colon, W., "Microanalysis: Biosensors at the Point of Care", <i>MST News</i> 01/04, pages 9-11.			
Cl. A	115	Duley, W.W. "UV Lasers: effects and applications in materials science", Chapter 3 Photochemical and photothermal effects, Cambridge University Press, pages 78-97.			
Examiner	C. J. Bubes			Date Considered 10/5/05	
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U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

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**Complete if Known**

Application Number	10/601,144
Filing Date	20-Jun-03
First Named Inventor	Bhullar
Group Art Unit	Unknown
Examiner Name	Unknown <i>CARL J. Arbes</i>
Attorney Docket Number	BMID 8958 CIP

*(use as many sheets as necessary)*

Sheet	1	of	1
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Attorney Docket Number	BMID 9958 CIP
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Examiner Signature	<i>C. J. J. J.</i>	Date Considered	4/17/05
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REMARKS: Initial reference considered, whether or not citation is in conformance with MPEP 609. Drawn line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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